

**Notice of References Cited**

Application/Control No.

09/994,729

Applicant(s)/Patent Under

Reexamination

TAKESUE ET AL.

Examiner

David Buttner

Art Unit

1712

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0130434	07-2003	Statz et al.	525/329.5
	B	US-6,565,455	05-2003	Hayashi et al.	473/371
	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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